WAFER TEST CARD USING ELECTRIC CONDUCTIVE SPRING AS WAFER TEST INTERFACE

ABSTRACT

A wafer test card for testing the electric property of the chips on a wafer comprising a base board and a group of electric conductive springs or electric conductive spring pins connected to the base board and functioned as a wafer test interface to the wafer test card, the base board has a testing circuit thereon which forms electric connection with the electric conductive springs or electric conductive spring pins; when carrying out wafer test, even if the elevation of the pad of each individual chip is different from each other, the electric conductive spring or electric conductive spring pin of the wafer test card shall still keep correctly touching the pad of chip to obtain better and more stable electric property test result, and avoid mistake in identifying the chip.

Figure 8.